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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): FUKUDA et al.

Serial No.: 10/699,784

Filed: November 4, 2003

Title: SEMICONDUCTOR DEVICE HAVING

RADIATION STRUCTURE

Atty. Dkt.: 01-103-CON7

Group Art Unit: 2826

Examiner: Unknown

Commissioner for Patents Arlington, VA 22202

Date: August 10, 2004

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

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Pursuant to 37 C.F.R. §1.56, the references listed on the attached Form PTO-1449 are being brought to the attention of the Examiner without any admission that they constitute statutory prior art, or without any admission that they contain subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

Further, pursuant to 37 C.F.R. §1.97(e), the undersigned hereby certifies that each listed reference was cited in a Communication (copy enclosed) from a foreign patent office in connection with a counterpart foreign application not more than three months prior to the filing of this statement.

Although no fees are believed to be due at this time, it is respectfully requested that any such fees be charged to Deposit Account 50-1147. Also, the Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed references have been considered and made of record.

Respectfully submitted.

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PATENT APPLICATION

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FORM PTO-1449	ATTY. DKT NO.	01-103-CON7	SER. NO.	10/699,784	
	APPLICANT	FUKUDA et al.			
	FILING DATE	November 4, 2003	GROUP	2826	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

TRANSLATION

						IKANSLAI	I ION
DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
JP-A-10-125700	05/15/98	JAPAN		,		Engl. Abstract	
JP-A-61-147539	07/05/86	JAPAN				Engl. Abstract	
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^{*} Full English text of the JP Document will be available in machine-translated form from JP (Japanese Patent Office) English language web site at http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER		. DATE CONSIDERED	
Rev. 10/94 (Form	3.05)		